IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: **Youichi ARAI**

Serial Number: **Not Yet Assigned**
(**§371 of International Application PCT/JP05/00679**)

Filed: **June 7, 2006**

For. **METHOD OF MEASURING INTRINSIC RESISTANCE OF BATTERY AND APPARATUS OF SAME**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450   June 7, 2006

Sir:

In compliance with 37 CFR 1.56, Applicant calls to the attention of the Patent and

Trademark Office the references listed on the attached PTO-1449 and cited in the enclosed

international search report. References AE-AF are cited in the international search report.

A copy of each of the references is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please

charge Deposit Account No. 01-2340.

Respectfully submitted,
ARMSTRONG, KRATZ, QUINTOS,
HANSON & BROOKS, LLP
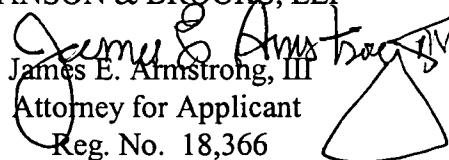
James E. Armstrong, III
Attorney for Applicant
Reg. No. 18,366

JEA/jaz
Atty. Docket No. **060424**
Suite 1000
1725 K Street, N.W.
Washington, D.C. 20006
(202) 659-2930

23850
PATENT TRADEMARK OFFICE

Enclosures: PTO-1449; References (3); International Search Report

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /JZ/

INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. 060424	Serial No. **New Application**
	Applicant(s): **Youichi ARAI**	
	Filing Date: **June 7, 2006**	Group Art Unit: **Not Yet Assigned**

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
_____	AA						
_____	AB						
_____	AC						
_____	AD						

FOREIGN PATENT DOCUMENTS

Examiner		Document No.	Date	Country	Translation (Yes or No)
/JZ/	AE	2003-177163	06/27/03	Japan	No
/JZ/	AF	2003-177164	06/27/03	Japan	No
/JZ/	AG	2003-115331	04/18/03	Japan	Yes-Abstract/Discussed in the specification
_____	AH				
_____	AI				

OTHER DOCUMENTS

_____	AJ	
_____	AK	

Examiner	/Jue Zhang/	Date Considered	09/01/2008

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /JZ/